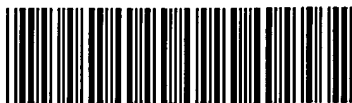


**Search Notes**

Application/Control No.

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Examiner

Amelia Rutledge

Applicant(s)/Patent under  
Reexamination

CHEN ET AL.

Art Unit

2176

**SEARCHED**

Class	Subclass	Date	Examiner
715	512	2/15/2006	AR

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST(US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB) -See Search History Printout	2/15/2006	AR
ACM Digital Library search - see search printouts	2/15/2006	AR
IEEE Xplore database search	2/15/2006	AR